

Application/Control No.	Applicant(s)/Patent under Reexamination
10/796,587	NAIINI ET AL.
Examiner	Art Unit
John S. Chu	1752

	SEARCHED				
Class	Subclass	Date	Examiner		
430	190	11/2005	ye		
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430	326				
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528	335,338				
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528	347				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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